PH1225AL

N-channel 25 V 1.2 m Ω logic level MOSFET in LFPAK

Rev. 01 — 14 October 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel MOSFET in LFPAK package qualified to 150 °C. This product is for computing use only

1.2 Features and benefits

- Advanced TrenchMOS provides low RDSon and low gate charge
- High efficiency gains in switching power converters
- Improved mechanical and thermal characteristics
- LFPAK provides maximum power density in a Power SO8 package

1.3 Applications

For computing use only

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$		-	-	25	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	[1]	-	-	100	Α
P _{tot}	total power dissipation	$T_{mb} = 25 ^{\circ}C; \text{ see } \underline{\text{Figure 2}}$		-	-	121	W
Tj	junction temperature			-55	-	150	°C
Avalanci	he ruggedness						
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; V_{sup} ≤ 25 V; R_{GS} = 50 Ω ; unclamped		-	-	677	mJ
Dynamic	characteristics						
Q_{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$		-	11.9	-	nC
Q _{G(tot)}	total gate charge	$V_{DS} = 12 V;$ see <u>Figure 12</u> and <u>13</u>		-	50.6	-	nC
Static ch	aracteristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 100 \text{ °C}; \text{ see } \frac{\text{Figure 11}}{\text{ or } 100 \text{ or } 1000 \text{ or } 100 \text{ or } 100 \text{ or } 100 \text{ or }$		-	-	1.6	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 10}}{ Implies to the content of t$		-	0.9	1.2	mΩ

^[1] Continuous current is limited by package.



N-channel 25 V 1.2 mΩ logic level MOSFET in LFPAK

2. Pinning information

Table 2. Pinning information

Symbol	Description	Simplified outline	Graphic symbol
S	source		_
S	source		D
S	source		
G	gate		
D	drain		mbb076 S
		1 2 3 4 SOT1023	
	S S S G	S source S source G gate	S source S source G gate D drain

3. Ordering information

Table 3. Ordering information

Type number	Package						
	Name	Description	Version				
PH1225AL	LFPAK2	Plastic single-ended surface-mounted package (LFPAK2); 4 leads	SOT1023				

4. Limiting values

Table 4. Limiting values

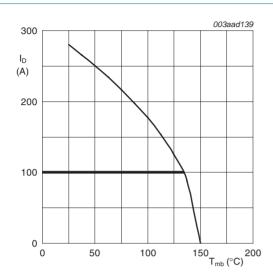
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C		-	25	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	25	V
V_{GS}	gate-source voltage			-20	20	V
I_D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	<u>[1]</u>	-	100	Α
		$V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	<u>[1]</u>	-	100	А
I_{DM}	peak drain current	$t_p \le 10 \mu\text{s}; \text{ pulsed}; T_{mb} = 25 ^{\circ}\text{C}; \text{ see } \underline{\text{Figure 3}}$		-	815	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	121	W
T _{stg}	storage temperature			-55	150	°C
Tj	junction temperature			-55	150	°C
$T_{sld(M)}$	peak soldering temperature			-	260	°C
Source-dr	ain diode					
Is	source current	T _{mb} = 25 °C;	<u>[1]</u>	-	100	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	815	Α
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; $V_{sup} \le$ 25 V; R_{GS} = 50 Ω ; unclamped		-	677	mJ

^[1] Continuous current is limited by package.

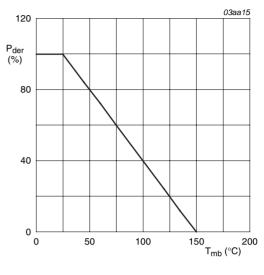
PH1225AL_1 © NXP B.V. 2009. All rights reserved.

N-channel 25 V 1.2 mΩ logic level MOSFET in LFPAK



 $V_{GS} \ge 5V(1)$ Capped at 100A due to package

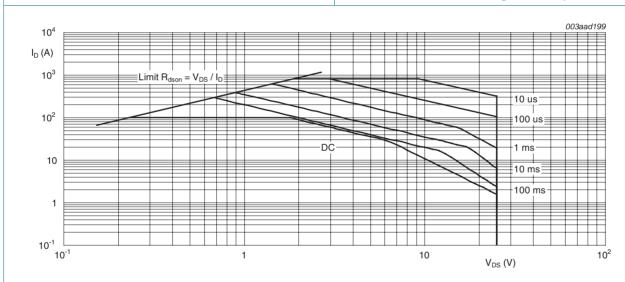
Continuous drain current as a function of Fig 1. mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

3 of 12

Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{sp} = 25 \,^{\circ}C; I_{DM}$ is single pulseCapped at 100A due to package

Safe operating area; continuous and peak drain currents as a function of drain-source voltage Fig 3.

N-channel 25 V 1.2 mΩ logic level MOSFET in LFPAK

Thermal characteristics

Thermal characteristics Table 5.

Product data sheet

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j\text{-}mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	0.4	1	K/W

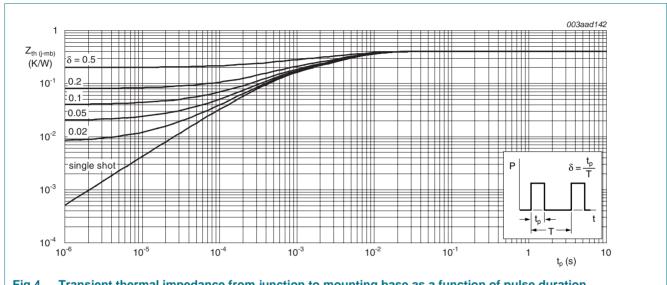


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

4 of 12

N-channel 25 V 1.2 m Ω logic level MOSFET in LFPAK

6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	25	-	-	V
	breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ}C$	22	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see <u>Figure 8</u> and <u>9</u>	1.3	1.7	2.15	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 150 \text{ °C}$; see Figure 9	0.65	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see Figure 9	-	-	2.45	V
I _{DSS}	drain leakage current	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1.5	μΑ
		$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	500	μΑ
I_{GSS}	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nΑ
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 10</u>	-	1.2	1.85	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 100 ^{\circ}\text{C};$ see <u>Figure 11</u>	-	-	1.6	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 ^{\circ}\text{C};$ see <u>Figure 11</u>	-	-	2.1	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 10	-	0.9	1.2	mΩ
R_{G}	gate resistance		-	0.94	-	Ω
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 12</u> and <u>13</u>	-	105	-	nC
		$I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$;	-	50.6	-	nC
Q_{GS}	gate-source charge	see Figure 12 and 13	-	19.3	-	nC
$Q_{GS(th)}$	pre-threshold gate-source charge		-	8.1	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	4.5	-	nC
Q_{GD}	gate-drain charge		-	11.9	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	V _{DS} = 12 V; see <u>Figure 12</u>	-	2.6	-	V
C _{iss}	input capacitance	$V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	6380	-	pF
C _{oss}	output capacitance	$T_j = 25$ °C; see <u>Figure 14</u>	-	1640	-	pF
C _{rss}	reverse transfer capacitance		-	644	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 12 \text{ V}; R_L = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	69	-	ns
t _r	rise time	$R_{G(ext)} = 5.6 \Omega$	-	125	-	ns
t _{d(off)}	turn-off delay time		-	94	-	ns
·u(oii)						

N-channel 25 V 1.2 mΩ logic level MOSFET in LFPAK

Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dr	ain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 15</u>	-	0.78	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	52	-	ns
Q _r	recovered charge	$V_{DS} = 20 \text{ V}$	-	66	-	nC

[1] Tested to JEDEC standards where applicable.

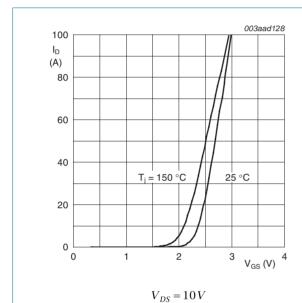


Fig 5. Transfer characteristics: drain current as a function of gate-source voltage; typical values

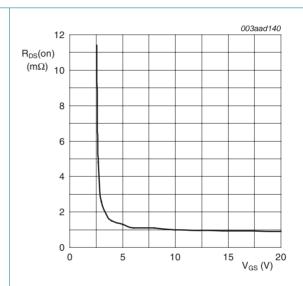


Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values

 $T_i = 25 \,^{\circ}C; I_D = 15A$

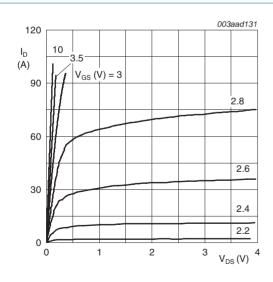
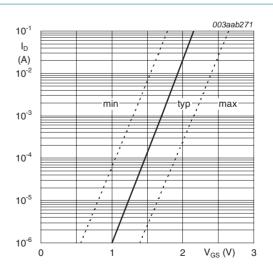


Fig 7. Output characteristics: drain current as a function of drain-source voltage; typical values

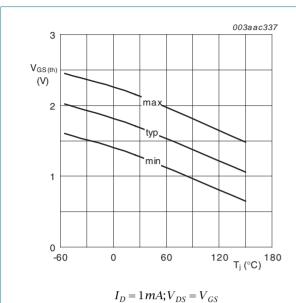
 $T_j = 25 \,^{\circ}C; t_p = 300 \,\mu s$



 $T_j = 25 \,^{\circ}C; V_{DS} = 5 V$

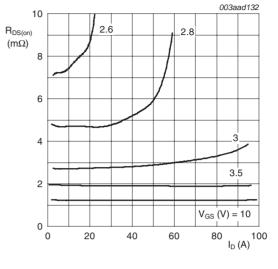
Fig 8. Sub-threshold drain current as a function of gate-source voltage

N-channel 25 V 1.2 mΩ logic level MOSFET in LFPAK



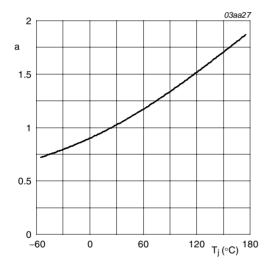
D , *D* , *G*

Fig 9. Gate-source threshold voltage as a function of junction temperature



 $T_j = 25 \,^{\circ}C; t_p = 300 \,\mu s$

Fig 10. Drain-source on-state resistance as a function of drain current; typical values



 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$

Fig 11. Normalized drain-source on-state resistance factor as a function of junction temperature

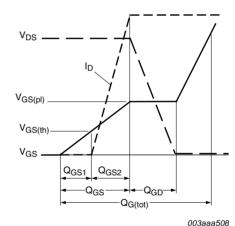
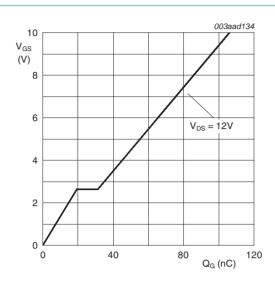


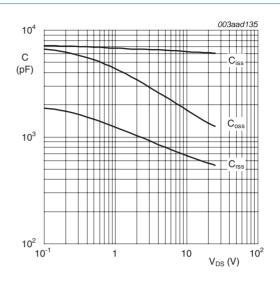
Fig 12. Gate charge waveform definitions

N-channel 25 V 1.2 mΩ logic level MOSFET in LFPAK



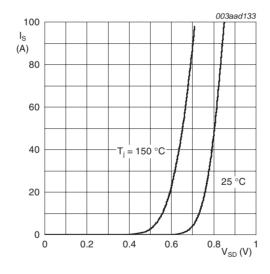
 $T_i = 25 \,^{\circ}C; I_D = 10A$

Fig 13. Gate-source voltage as a function of gate charge; typical values



$$V_{GS} = 0V; f = 1MHz$$

Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $V_{GS} = 0V$

Fig 15. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

N-channel 25 V 1.2 mΩ logic level MOSFET in LFPAK

7. Package outline

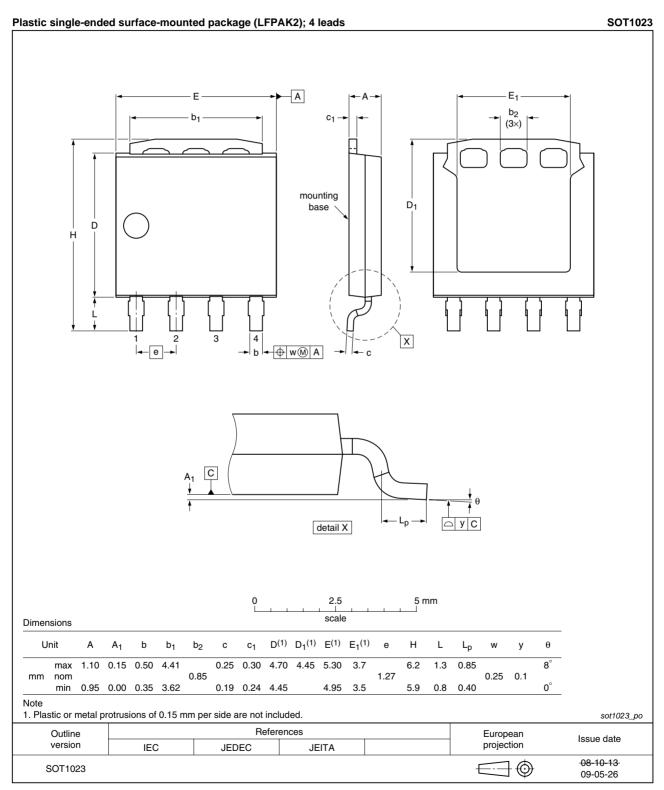


Fig 16. Package outline SOT1023 (LFPAK2)

N-channel 25 V 1.2 m Ω logic level MOSFET in LFPAK

Revision history

Table 7. **Revision history**

Product data sheet

Document ID	Release date	Data sheet status	Change notice	Supersedes
PH1225AL_1	20091014	Product data sheet	-	-

10 of 12

N-channel 25 V 1.2 m Ω logic level MOSFET in LFPAK

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

9.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

9.3 Disclaimers

General — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Export control — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from national authorities.

9.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

TrenchMOS — is a trademark of NXP B.V.

10. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

PH1225AL 1 © NXP B.V. 2009. All rights reserved.

N-channel 25 V 1.2 m Ω logic level MOSFET in LFPAK

11. Contents

1	Product profile	1
1.1	General description	1
1.2	Features and benefits	1
1.3	Applications	1
1.4	Quick reference data	1
2	Pinning information	2
3	Ordering information	2
4	Limiting values	
5	Thermal characteristics	
6	Characteristics	5
7	Package outline	9
8	Revision history	
9	Legal information	
9.1	Data sheet status	. 11
9.2	Definitions	
9.3	Disclaimers	
9.4	Trademarks	
10	Contact information	11

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

